

THIRD WORKSHOP ON THIN FILM PHYSICS AND TECHNOLOGY,
including TOPICAL CONFERENCE ON MICROSTRUCTURE AND
SURFACE MORPHOLOGY EVOLUTION IN THIN FILMS (REPOSITORY
FOR LECTURE NOTES FROM THE SCANNED HISTORICAL ARCHIVE)
| (smr 1135)

Contribution ID : **56**

Type : **not specified**

X-RAY TECHNIQUES FOR THE CHARACTERISATION OF THIN FILMS AND LAYERED STRUCTURES

Content

Summary

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